



Diagnostic Methodology and Sensors Technologies

Guest Editors:

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Deadline for manuscript
submissions:

closed (31 August 2023)

Message from the Guest Editors

Papers should also present measurement methods, approaches, and principles for performance assessment through measurement, verification protocols, testing, and validation methods. Interdisciplinary contributions crossing boundaries within methodologies and measurements are especially welcome in the form of research papers, communications, review papers, and letters. There are multiple interconnections between apparently different research environments, and our goal is to combine the best research and technology in one Issue to ensure the safety and protection of humanity and the surrounding environment.

Keywords:

- Radiative Parameters
- Radiative Sensors
- Nuclear Sensors
- Linear Accelerator
- Mass Spectrometry
- Test Facility
- Heat Flux
- Calibration and Verification Techniques
- Thermal Protection System Properties
- Plasma Properties
- Sustainability and Environment Monitoring
- Anthropogenic Characterization and Observation
- Observation Technologies for Human Safety
- Airborne Technologies
- Radiation Hardness





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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